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(54) **Semiconductor laser device having InGaAs compressive-strain active layer, GaAsP tensile-strain barrier layers and InGaP optical waveguide layers**

Halbleiterlaservorrichtung mit einer aktiven Schicht aus InGaAs unter Kompressionsdruck, einer Sperrschicht aus GaAsP unter Dehnungsdruck, und einem Lichtwellenleiter aus InGaP

Laser semiconducteur doté d'une couche active d'InGaAs en compression, d'une barrière en GaAsP sous tension et d'un guide d'onde en InGaP

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